

# 200V N-Channel PowerTrench<sup>®</sup> MOSFET

### **General Description**

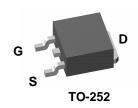
This N-Channel MOSFET has been de signed specifically to improve the overal l efficiency of DC/DC converters u sing ei ther s ynchronous or conventional switching PWM controllers.

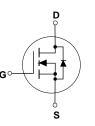
These M OSFETs f eature f aster s witching and lower gate c harge than ot her M OSFETs w ith comparable  $RDS_{(ON)}$  specifications.

The result is a MOSFET that is easy and safer to drive (even at very hi gh f requencies), and DC/DC power supply designs with higher overall efficiency.

## Features

- 3.6 A, 200 V.  $R_{\text{DS(ON)}}$  = 130 m  $\Omega$  @ V\_{GS} = 10 V
- Low gate charge
- Fas t switching speed
- High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- High power and current handling capability





## Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		200	V
V <sub>GSS</sub>	Gate-Source Voltage		±20	V
ID	Drain Current – Continuous	(Note 1)	3.6	A
	Drain Current – Pulsed		20	
PD	Maximum Power Dissipation @ T <sub>c</sub> = 25°C	(Note 1)	70	W
	@ T <sub>A</sub> = 25°C	(Note 1a)	3.2	
	@ T <sub>A</sub> = 25°C	(Note 1b)	1.3	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	3.2	V/ns
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	1.8	°C/W
R <sub>0JA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

# Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDD2670	FDD2670	13"	16mm	2500 units

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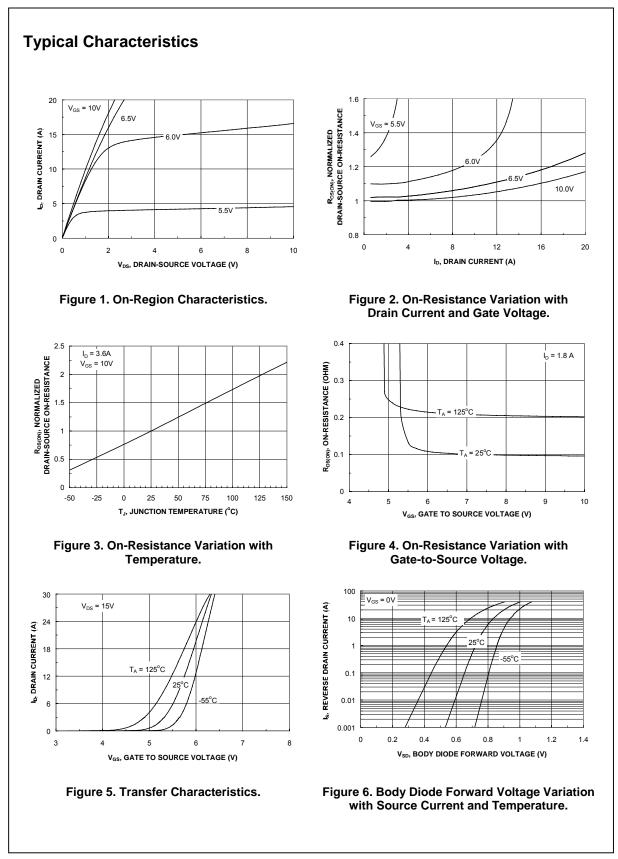
ce Avalanche Ratings (Note ngle Pulse Drain-Source valanche Energy aximum Drain-Source Avalanche urrent teristics ain–Source Breakdown Voltage eakdown Voltage Temperature pefficient ero Gate Voltage Drain Current ate–Body Leakage, Forward ate–Body Leakage, Reverse	$V_{DD} = 100 \text{ V},  I_D = 3.6 \text{ A}$ $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$ $I_D = 250 \mu\text{A}, \text{ Referenced to } 25^{\circ}\text{C}$ $V_{DS} = 160 \text{ V},  V_{GS} = 0 \text{ V}$	200	214	375 3.6	MJ A V
ngle Pulse Drain-Source valanche Energy aximum Drain-Source Avalanche urrent teristics aain–Source Breakdown Voltage eakdown Voltage Temperature pefficient ero Gate Voltage Drain Current ate–Body Leakage, Forward	$V_{DD} = 100 \text{ V},  I_D = 3.6 \text{ A}$ $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$ $I_D = 250 \mu\text{A}, \text{ Referenced to } 25^{\circ}\text{C}$ $V_{DS} = 160 \text{ V},  V_{GS} = 0 \text{ V}$	200	214		A
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befficient ero Gate Voltage Drain Current ate-Body Leakage, Forward	$I_D = 250 \ \mu\text{A}, \text{ Referenced to } 25^\circ\text{C}$ $V_{DS} = 160 \ \text{V},  V_{GS} = 0 \ \text{V}$		214	ι	
ate–Body Leakage, Forward					mV/°C
				1	μA
te Body Leakago Boyoroo	$V_{GS} = 20 V$ , $V_{DS} = 0 V$			100	NA
IC-DUUY LEARAYE, REVEISE	$V_{GS} = -20 V$ , $V_{DS} = 0 V$			-100	NA
eristics (Note 2)					
ate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	2	4	4.5	V
ate Threshold Voltage emperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		-10		mV/°C
atic Drain–Source 1–Resistance			100 205	130 275	mΩ
n-State Drain Current	$V_{GS}$ = 10 V, $V_{DS}$ = 5 V	20			А
orward Transconductance	$V_{DS} = 5 V$ , $I_D = 3.6 A$		15		S
haracteristics					
out Capacitance	$V_{DS} = 100 V$ , $V_{GS} = 0 V$ ,		1228		PF
utput Capacitance	f = 1.0 MHz		112		PF
everse Transfer Capacitance			17		pF
Characteristics (Note 2)					
ırn–On Delay Time	$V_{DD} = 100 V$ . $I_D = 1 A$ .	1	13	23	ns
ırn–On Delay Time ırn–On Rise Time	$V_{DD}$ = 100 V, $I_D$ = 1 A, V <sub>GS</sub> = 10 V, $R_{GEN}$ = 6 Ω		13 8	23 16	ns ns
	$V_{DD} = 100 \text{ V}, \qquad I_D = 1 \text{ A}, \\ V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$				
Irn–On Rise Time			8	16	ns
rn–On Rise Time rn–Off Delay Time	V <sub>GS</sub> = 10 V, R <sub>GEN</sub> = 6 Ω		8 30	16 48	ns ns
rn–On Rise Time rn–Off Delay Time rn–Off Fall Time			8 30 25	16 48 40	ns ns ns
rrn–On Rise Time rrn–Off Delay Time rrn–Off Fall Time tral Gate Charge	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$ $V_{DS} = 100 \text{ V}, \qquad I_D = 3.6 \text{ A},$		8 30 25 27	16 48 40	ns ns ns nC
rrn–On Rise Time rrn–Off Delay Time rrn–Off Fall Time tal Gate Charge ate–Source Charge ate–Drain Charge	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$ $V_{DS} = 100 \text{ V}, \qquad I_D = 3.6 \text{ A},$ $V_{GS} = 10 \text{ V}$		8 30 25 27 7	16 48 40	ns ns nS nC nC
rrn–On Rise Time Irrn–Off Delay Time Irrn–Off Fall Time Irtal Gate Charge ate–Source Charge	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$ $V_{DS} = 100 \text{ V}, \qquad I_D = 3.6 \text{ A},$ $V_{GS} = 10 \text{ V}$ and Maximum Ratings		8 30 25 27 7	16 48 40	ns ns nS nC nC
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Scale 1 : 1 on letter size paper

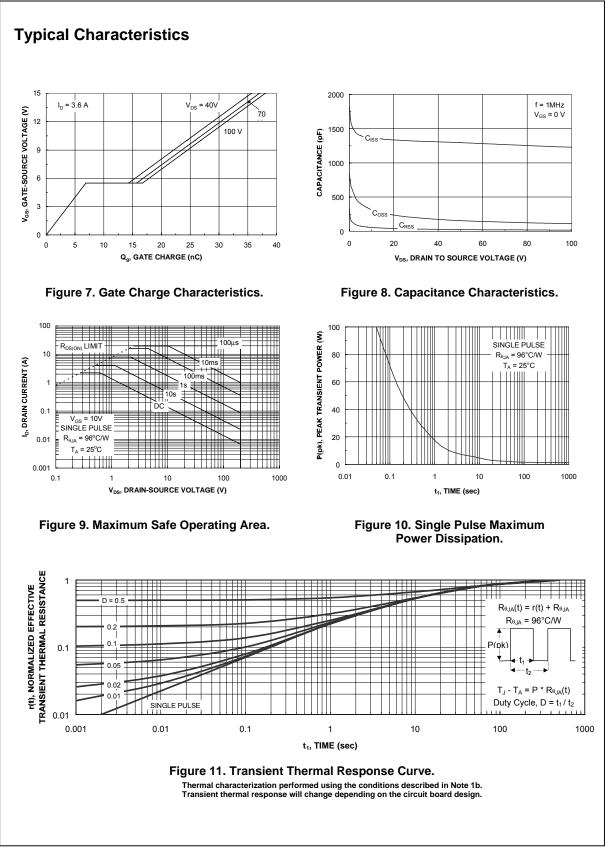
2. Pulse Test: Pulse Width < 300 $\mu$ s, Duty Cycle < 2.0%

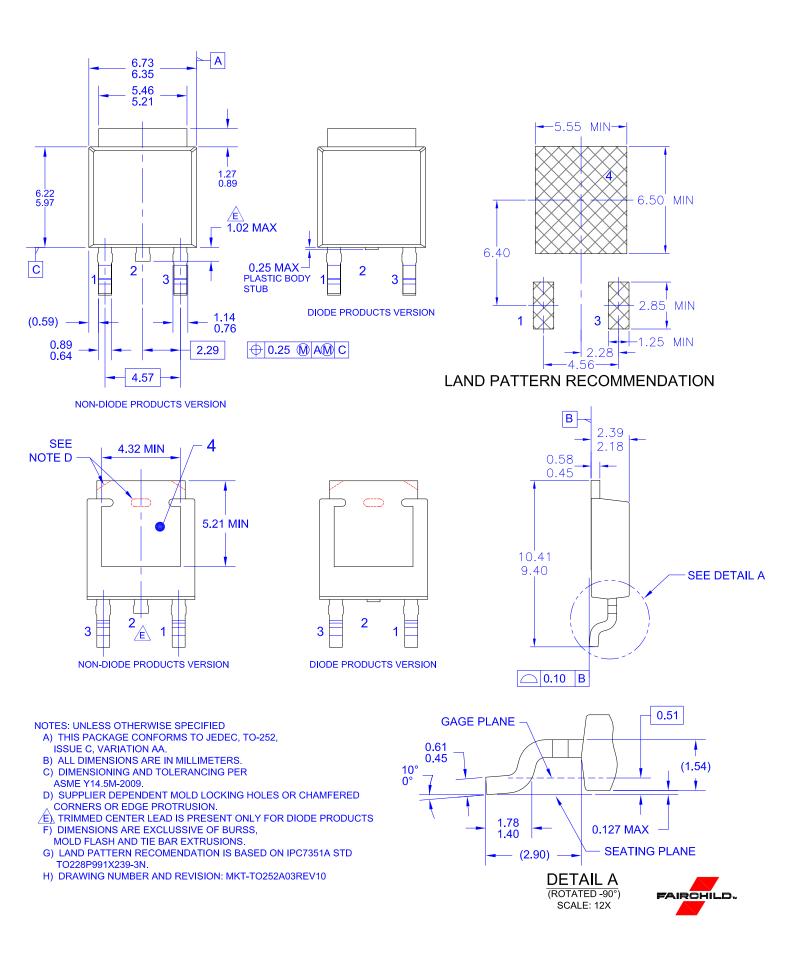
3.  $I_{SD} \leq$  3A, di/dt  $\leq$  100A/µs,  $V_{DD} \leq BV_{DSS},~Starting~T_{J}$  = 25°C

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